

## **Quarterly Reliability Monitoring Results**

## Quarters: Q1/2022 to Q4/2023

Based on structural similarity

Supplier Nexperia B.V.		User Part Number						
		MJD42C						
Name of Laboratory  Nexperia ATGD  Based on AEC-Q101 Test		Part Description						
		Nexperia DHAM Small Signal Bipolar Transistor						
		SOT428, Subcon TFME						
		Test Conditions	Duration	# Lots	# Quantity	# Rejects		
	TEST							
	Pre- and Post-Stress							
# 1	Electrical Test	Tamb = 25 °C	N/A	see below	all parts	see below		
		JESD22-A113						
		Bake Tamb = 125 °C	24 hours					
	PC	Soak Tamb = 85 °C, RH = 85%	168 hours					
# 2	Preconditioning	Reflow soldering	3 cycles	108	4320	0		
		MIL-STD-750-1						
	HTRB	M1039 Method A						
<i>"</i> –	Bias	Tj = Tjmax, Vr = 100% of max. datasheet reverse voltage	1000 5	415	10000	0		
# 5	DidS	reverse voltage	1000 hours	415	18680	0		
	тс	JESD22-A104						
# 7	Temperature Cycling	-65 °C to Timax, not to exceed 150°C	500 cycles	19	840	0		
π /			300 Cycles	17	040	0		
	UHAST	JESD22-A118						
# 8 <b>o</b> r	Unbiased HAST	Tamb = 130 °C, RH = 85 %	— 96 hours	19	840	0		
		JESD22-A102						
	AC	Tamb = 121 °C, RH = 100 %						
# 8a	Autoclave	Pressure = 205 kPa (29.7 psia)						
	H3TRB	JESD22-A101						
	High Humidity High	Tamb = 85 °C, RH = 85%, VR = 80 % of						
# 9	Temperature Reverse Bias	rated reverse voltage <sup>[1]</sup>	1000 hours	19	840	0		
		MIL-STD-750 Method 1037						
	IOL	ton = toff, devices powered to insure $\Delta Tj$ =						
# 10	Intermittent Operating Life	100 °C	333 hours	19	840	0		
	BCII	JECD22 A111						
" 20	RSH Resistance to Solder Heat	JESD22-A111 260 °C ± 5 °C		22	0.50	•		
# 20		200 ·C ± 5 *C	10 s	32	960	0		
# 21	<b>SD</b> Solderability	J-STD-002		0	240	0		
# 21	Joinel ability	J-31D-002		8	240	0		

<sup>[1]</sup> The maximum applied voltage is limited by test chamber set up and does not exceed 115V.

## Calculation of FIT and MTTF

Test considered for FIT calculation: High Temperature Reverse Bias (HTRB, Test #B1) Confidence level 60%, derated to 55 °C, activation energy 0.7 eV, test time 168 to 1000 hours

Wafer Fab	Technology	Quantity	Rejects	Failure Rate (FIT)	MTTF (hrs)
Nexperia	Small Signal Bipolar				
DHAM	Transistor	18680	0	0,23	4,40E+09

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